TOSHIBA Transistor Silicon NPN Epitaxial Type

TPCP8701

Portable Equipment Applications
Switching Applications
Inverter Lighting Applications

• Small footprint due to small and thin package

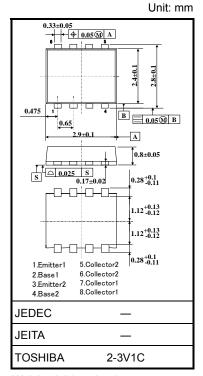
• High DC current gain : $h_{FE} = 400$ to 1000 (IC = 0.3 A)

• Low collector-emitter saturation : V_{CE} (sat) = 0.14 V (max)

• High-speed switching: $t_f = 120 \text{ ns (typ.)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V _{CBO}	100	V	
Collector-emitter voltage		V _{CEX}	80	٧	
		V _{CEO}	50	V	
Emitter-base voltage		V _{EBO}	7	٧	
Collector current	DC (Note 1)	I _C	3.0	А	
	Pulse (Note 1)	I _{CP}	5.0		
Base current		Ι _Β	300	mA	
Collector power dissipation (t = 10s)	Single-device operation		1.77		
	Single-device value at dual operation	P _C (Note 2)	0.95	W	
Collector power dissipation (DC)	Single-device operation		0.94		
	Single-device value at dual operation	P _C (Note 2)	0.54	W	
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	



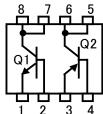
Weight: 0.017 g (typ.)

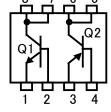
- Note 1: Please use devices on condition that the junction temperature is below 150°C.
- Note 2: Mounted on FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm²)
- Note 3: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Figure 1. Circuit configuration (top view)

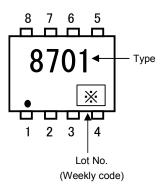
Figure 2. Marking (Note 4)





Note 4: • on lower left on the marking indicates Pin 1.

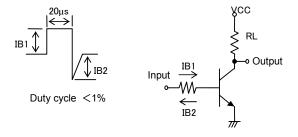
※ Weekly code: (Three digits) Week of manufacture (01 for first week of year, continues up to 52 or 53) Year of manufacture (One low-order digits of calendar year)

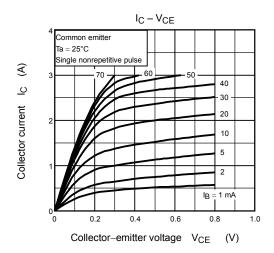


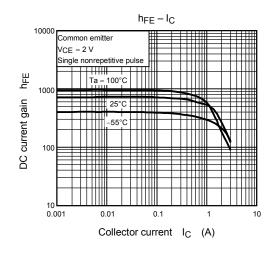
Electrical Characteristics (Ta = 25°C)

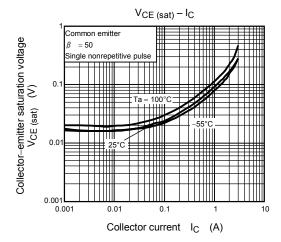
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I _{CBO}	V _{CB} = 100 V, I _E = 0	_	_	100	nA
Emitter cut-off current		I _{EBO}	$V_{EB} = 7 \text{ V}, I_{C} = 0$	_	_	100	nA
Collector-emitter brakedown voltage		V (BR) CEO	$I_C = 10 \text{ mA}, I_B = 0$	50	_	_	V
DC current gain		h _{FE} (1)	$V_{CE} = 2 \text{ V}, I_{C} = 0.3 \text{ A}$	400	_	1000	
		h _{FE} (2)	V _{CE} = 2 V, I _C = 1 A	200	_	_	
Collector-emitter saturation voltage		V _{CE (sat)}	I _C = 1 A, I _B = 20 mA	_	_	0.14	V
Base-emitter saturation voltage		V _{BE (sat)}	I _C = 1 A, I _B = 20 mA	_	_	1.10	V
Collector output capacitance		C _{ob}	V _{CB} = 10 V, I _E = 0, f = 1MHz	_	13	_	pF
Switching time	Rise time	t _r	See Figure 3 circuit diagram $V_{CC} \simeq 30 \text{ V}, \text{ R}_L = 30 \Omega$ $I_{B1} = -I_{B2} = 33.3 \text{ mA}$	_	40	_	ns
	Storage time	t _{stg}		_	500	_	
	Fall time	t _f		_	120	_	

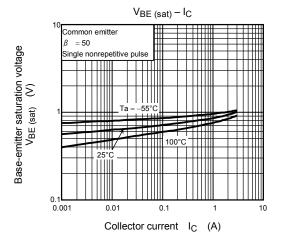
Figure 3. Switching Time Test Circuit & Timing Chart

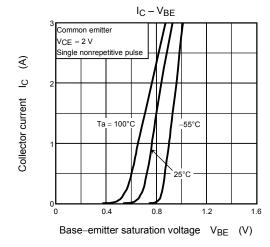


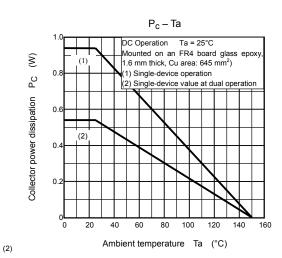




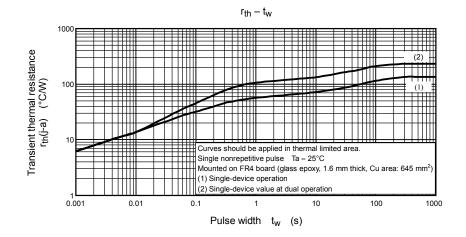


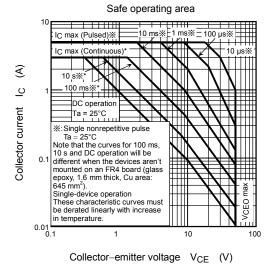


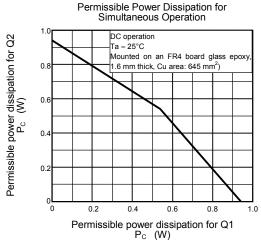




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Collector power dissipation at the single-device operation is 0.94W. $\label{eq:collector} % \begin{subarray}{ll} \end{subarray} % \begin{subarr$

Collector power dissipation at the single-device value at dual operation is 0.54W.

Collector power dissipation at the dual operation is set to 1.08W.

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Handbook" etc..

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